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| Notice of References Cited | Application/Control No. 10/636,035 | Applicant(s)/Patent Under Reexamination BHAT ET AL. | |
| | Examiner Jennifer M. Kennedy | Art Unit 2812 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-6,743,475 B2 | 06-2004 | Skarp et al. | 427/255.31 |
| | B | US-2002/0135048 A1 | 09-2002 | Ahn et al. | 257/632 |
| | C | US-6,469,333 B1 | 10-2002 | Takai et al. | 257/295 |
| | D | US-6,358,789 B2 | 03-2002 | Lee, Sang-Hyeob | 438/239 |
| | E | US-6,777,776 B2 | 08-2004 | Hieda, Katsuhiko | 257/532 |
| | F | US-2002/0086556 A1 | 07-2002 | Ahn et al. | 438/785 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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